# N-Channel 20V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
20	0.012 at V <sub>GS</sub> = 10 V	12	6.1 nC		
	0.015 at V <sub>GS</sub> = 4.5 V	11	0.1110		

**SO-8** 

Top View

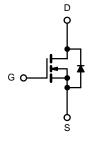
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# **FEATURES**

- · Halogen-free
- TrenchFET® Power MOSFET
- Optimized for High-Side Synchronous **Rectifier Operation**
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested

#### **APPLICATIONS**

- · Notebook CPU Core
  - High-Side Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	T <sub>A</sub> = 25 °C, unles	s otherwise n	oted		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	$V_{DS}$	20	V		
Gate-Source Voltage	$V_{GS}$	± 16	V		
	T <sub>C</sub> = 25 °C		12		
Continuous Proin Current (T = 150 °C)	T <sub>C</sub> = 70 °C	I <sub>D</sub>	11		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C		10 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		8 <sup>b, c</sup>	_	
Pulsed Drain Current	I <sub>DM</sub>	47	Α		
Continuous Source Prais Diade Current	T <sub>C</sub> = 25 °C		3.7		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.0 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	20		
Avalanche Energy	L = 0.1 IIII	E <sub>AS</sub>	21	mJ	
	T <sub>C</sub> = 25 °C		4.1		
Maximum Dawar Dissination	T <sub>C</sub> = 70 °C	D.	2.5	147	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.2 <sup>b, c</sup>	W	
	T <sub>A</sub> = 70 °C		1.3 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	39	55	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	25	29	7	

#### Notes:

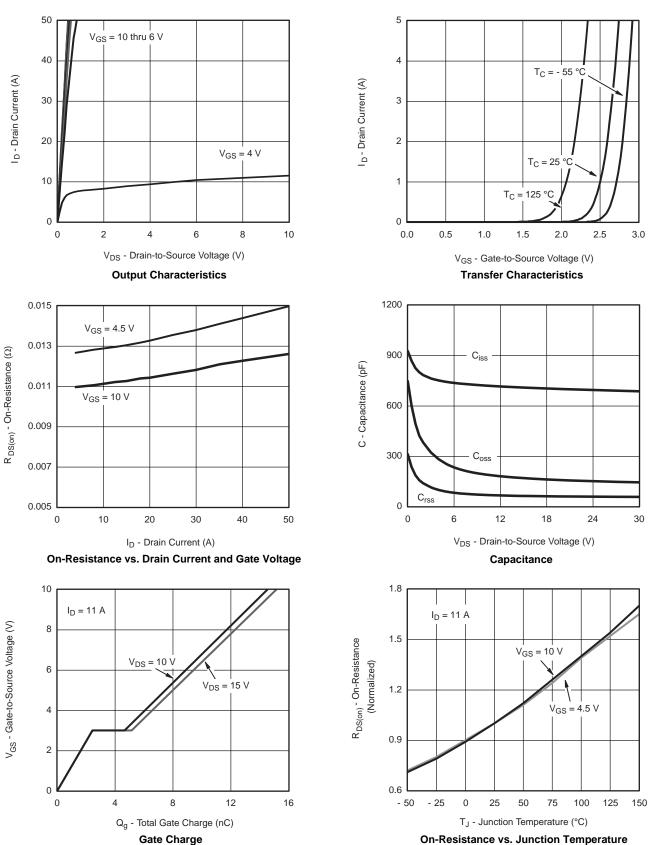
- a. Base on T<sub>C</sub> = 25 °C.
  b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	<u> </u>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		26		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Cata Valta da Duain Comunit	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			1	μΑ	
Zero Gate Voltage Drain Current		$V_{DS} = 20V$ , $V_{GS} = 0$ V, $T_{J} = 55$ °C	1		10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		0.012		6	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 9 A		0.015		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A		50		S	
Dynamic <sup>b</sup>				1		ı	
Input Capacitance	C <sub>iss</sub>			800		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		165			
Reverse Transfer Capacitance	C <sub>rss</sub>			73			
· ·	Q <sub>g</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		15	23		
Total Gate Charge				6.8	10.2	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5			
Gate-Drain Charge	$Q_{gd}$			2.3			
Gate Resistance	$R_g$	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			16	23		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 10 V, $R_L$ = 1.4 $\Omega$		12	16		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22		
Fall Time	t <sub>f</sub>			10	18		
Turn-On Delay Time	t <sub>d(on)</sub>			8	16	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 10 V, $R_L$ = 1.4 $\Omega$		10	20	- - -	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	22		
Fall Time	t <sub>f</sub>			8	15		
<b>Drain-Source Body Diode Characterist</b>	ics			<u>'</u>	•		
Continuous Source-Drain Diode Current	I <sub>S</sub>	$T_C = 25  ^{\circ}C$			10	Λ.	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				50	Α	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			15	30	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 0 A dl/dt = 100 A/vs T = 25 °C		6	12	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		8			
Reverse Recovery Rise Time	t <sub>b</sub>			7		ns	

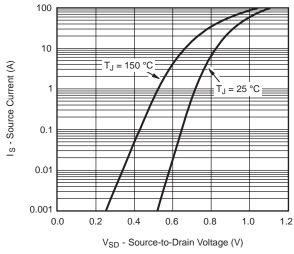
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

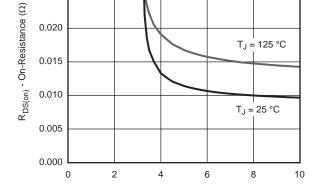
a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.

#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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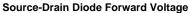


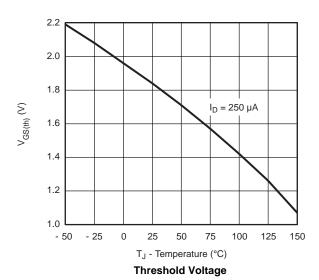


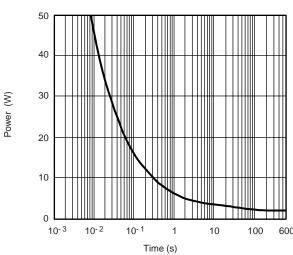
0.030

0.025

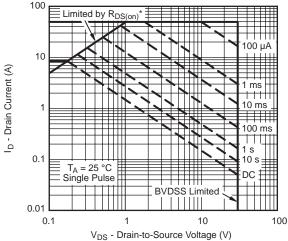
#### $\label{eq:VGS} \mbox{$V_{GS}$ - Gate-to-Source Voltage (V)}$ $\mbox{On-Resistance vs. Gate-to-Source Voltage}$







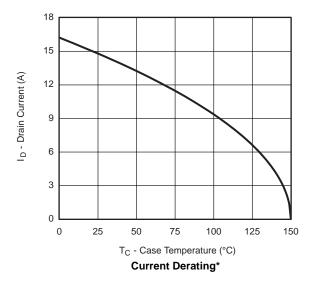
#### Single Pulse Power, Junction-to-Ambient

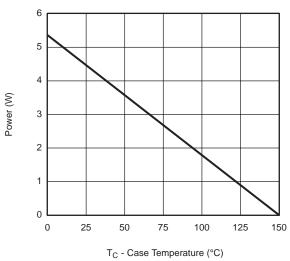


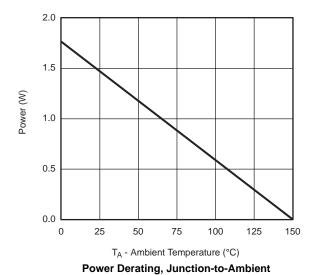
 $v_{DS}$  - Drain-to-Source voltage (V) \*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient

## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



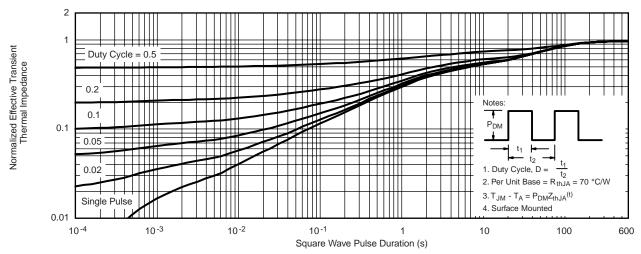




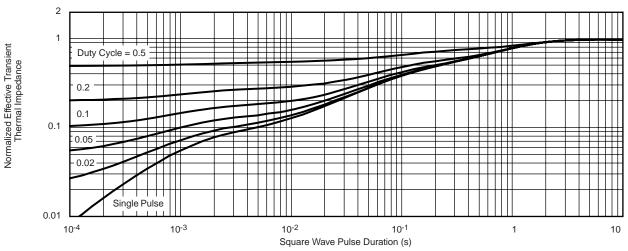
Power Derating, Junction-to-Foot

\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

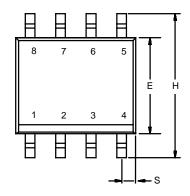


Normalized Thermal Transient Impedance, Junction-to-Ambient

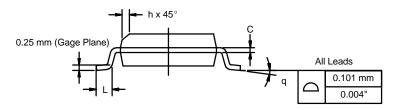


Normalized Thermal Transient Impedance, Junction-to-Foot

# SOIC (NARROW): 8-LEAD





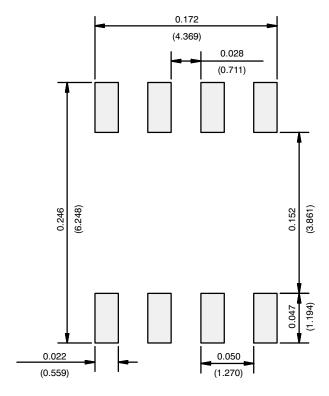


	MILLIMETERS		MILLIMETERS INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev. L. 11-Sep-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498

## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)

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